




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/669,253	MIYAI ET AL.	
	Examiner	Art Unit	
	Bernard E. Souw	2881	

ISSUE CLASSIFICATION											
ORIGINAL					CROSS REFERENCE(S)						
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
250		310			250	306	307	311			
INTERNATIONAL CLASSIFICATION					324	500	501	750	751		
G	0	1	N	13/16							
G	0	6	K	9/00							
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Bernard E. Souw (Assistant Examiner) (Date) 11/14/05					 JOHN R. LEE SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2000 (Primary Examiner) (Date) 11/14/05					Total Claims Allowed: 14	
 (Legal Instruments Examiner) (Date) 11/14/05										O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input checked="" type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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